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Communications

Novel p- and n-Type Organic Semiconductors with an Anthracene Unit

Shinji Ando,† Jun-ichi Nishida,† Eiichi Fujiwara,‡ Hirokazu Tada,† Youji Inoue,§ Shizuo Tokito,§ and Yoshiro Yamashita*.†

Department of Electronic Chemistry, Interdisciplinary Graduate School of Science and Engineering, Tokyo Institute of Technology, Nagatsuta, Midori-ku, Yokohama 226-8502, Japan, Institute for Molecular Science, Myodaiji, Okazaki 444-8585, Japan, and NHK Science and Technical Research Laboratories, Kinuta, Setagaya-ku, Tokyo 157-8510, Japan

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Organic semiconductors have been widely studied from viewpoints of their fundamental optoelectronic properties and their potential applications such as organic light-emitting diodes (OLEDs), organic field-effect transistors (OFETs), and photovoltaic cells. Usually hole-transporting (p-type) semiconductors have been prepared from electron-donating π -systems, whereas electron-transporting (n-type) semiconductors are prepared from electron-accepting ones. However, unusual n-type materials for OFETs have recently been obtained by introduction of fluoroalkyl substituents or a pentafluorophenyl substituent to thiophen oligomers which are known as hole-trasporting systems. Marks et al. have

reported that in OFETs with thiophene/perfluoroarene oligomers as active layers the terminal aryl groups have a great effect in determining the polarity of OFETs.4 This result suggests that novel p- and n-type organic semiconductors would be produced by introducing electron-accepting or electron-donating groups as terminal groups into a common core unit like thiophene oligomers. In the case of acenes, pentacene is known to exhibit the highest mobility ($\mu = 3.0$ cm²/Vs) among OFETs.⁵ Some derivatives of pentacene show p-type semiconducting behavior, 6 and perfluorination of pentacene has been reported to induce n-type semiconducting behavior. However, chemical modification of pentacene has a general difficulty caused by its low solubility in common organic solvents as well as instability in air. Therefore, we have paid our attention to anthracene⁸ which can be more easily derivatized owing to its better solubility.

^{*}To whom correspondence should be addressed. E-mail: yoshiro@echem.titech.ac.jp.

[†] Tokyo Institute of Technology.

[‡] Institute for Molecular Science.

[§] NHK Science and Technical Research Laboratories.

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Chart 1. Structure of Anthracene Derivatives

Scheme 1. Synthesis of Compounds 1 and 2

The OFETs with anthracene dimers or trimers as active layers have exhibited good hole mobilities, 9 suggesting that the π -extension of the anthracene unit by introducing aryl groups would afford efficient charge transportation systems. In this context, we have now designed novel anthracene derivatives having thiophene and 4-trifluormethylphenyl rings as electron-donating and accepting parts, respectively, for p- and n-type transistor materials. We report herein the synthesis and characterization of 2,6-bis(4-trifluoromethylphenyl)anthracene (1) and 2,6-dithienylanthracene (2) (Chart 1). OFETs using these derivatives have been constructed and their performances as p- and n-type semiconductors are presented here.

The syntheses of anthracene derivatives 1 and 2 were conveniently achieved as outlined in Scheme 1. Trifluoromethylphenyl derivative 1 was synthesized by the Suzuki coupling reaction of 2,6-dibromoanthracene (3)¹⁰ and 4-trifluromethylphenylboronic acid with Pd(PPh₃)₄ in refluxing toluene in 48% yield. On the other hand, thiophene derivative 2 was synthesized by the Stille coupling reaction using 2-tributylstannylthiophene in 73% yield. Compounds 1 and 2 were purified by sublimation and the structures were determined by the spectral data along with elemental analysis. Both compounds are bright-yellow color and have low solubility in common organic solvents. Differential scanning calorimetry (DSC) measurements showed a sharp melting endotherm peak at 289 °C for 1 and 322 °C for 2, respectively.

The absorption and emission spectral data of these derivatives are summarized in Table 1. The absorption maximum of 1 with electron-withdrawing units is blue-shifted compared to that of 2 with electron-donating thienyl units. The HOMO-LUMO gaps obtained from the end-absorptions are 2.85 eV for 1 and 2.68 eV for 2.¹¹ The lower

Table 1. Absorption and Fluorescene Maxima of 1 and 2 in the Chloroform Solution and Solid State^a

compound	solution		solid
	λ_{abs} [nm]	λ _{em} [nm]	$\overline{\lambda_{\rm em} [\rm nm]}$
1	379	439	517
2	392	431	490

^a Excitation wavelength: 365 nm.

gap for 2 is probably attributed to the less steric hindrance between the five-membered ring and anthracene unit, which leads to more effective π -conjugation. On the other hand, the emission maximum of 1 (439 nm) in chloroform appears at a longer wavelength than that of 2 (431 nm). The larger Stokes shift observed in 1 can be explained by considering that the geometry of 1 becomes more planar in the excited state. Moreover, 1 and 2 exhibited strong green photoluminescence in the solid state. The emission maxima were observed at longer wavelengths than those in solution (59–78 nm red shift), indicating the presence of strong intermolecular interactions in the solid state.

The electrochemical measurements of these derivatives 1 and 2 were performed in tetrahydrofuran. The differential pulse voltammogram (DPV) of 1 with acceptor units exhibited one oxidation peak (+1.43 V vs SCE) and one reduction peak (-1.68 V vs SCE). DPV of 2 with donor units showed two oxidation peaks (+1.20 V, +1.58 V vs SCE) and one reduction peak (-1.76 V vs SCE). Both oxidation and reduction potentials of 1 are a little higher than those of 2. This result indicates that 1 has a higher ionization potential and a higher electron affinity than 2.

The single crystal of **1** was obtained by slow sublimation. To investigate the molecular structure and intermolecular interactions in the soild state, X-ray structure analysis of the single crystal of **1** was carried out. As expected, the molecule of **1** has a little twisted geometry, where a torsion angle of 32.2° is observed between the anthracene and 4-trifluromethylphenyl rings. In the crystal, the intermolecular short C–C contact of 3.43 Å is observed between the C4 positions of anthracene rings. The molecules of **1** are packed in a herringbone manner as shown in Figure 1c, where the anthracene ring is overlapped with the 4-trifluoromethylphenyl rings.

FETs with these derivatives were constructed on SiO₂/Si substrates using a top-contact geometry (Figure 2a). An n-type Si wafer and a 200 nm thick layer of thermally grown SiO₂ were used as the gate and gate insulator, respectively. The thin films of these derivatives (50 nm) were formed on the SiO₂ by high-vacuum evaporation at different substrate temperatures. Gold source and drain contacts (50 nm) were deposited on the organic layer through a shadow mask. The channel length (L) and width (W) are 100 and 1000 μ m, respectively. The FET measurements were carried out at room temperature in a vacuum chamber (10^{-5} Pa) without

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⁽¹¹⁾ This is in agreement with the result of PM3 calculations: The HOMO– LUMO energy gaps of 1 and 2 show 6.91 and 6.87 eV, respectively.

⁽¹²⁾ Measured at a Pt electrode with 0.1 mol dm⁻³ Bu₄NPF₆ as a supporting electrolyte in THF.

⁽¹³⁾ See Supporting Information for semilogarithmic plot of source-drain current versus gate voltage and plot of square root of source-drain current versus gate voltage, for OFETs using 1 and 2 as semiconducting material, from which field-effect mobility, I_{on}/I_{off} ratio, and threshold voltage can be calculated.

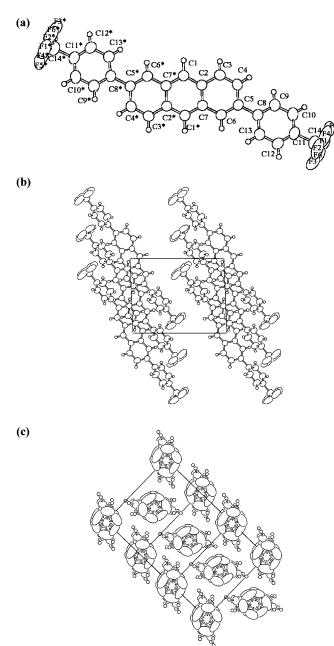


Figure 1. X-ray structure of anthracene derivative 1: (a) ORTEP drawing of the molecular structure, (b) overlapping view along the b-axis, and (c) packing structure.

exposure to air. Transistor responses were observed only for positive bias for 1, and for negative bias for 2 (Figures 2b and 2c), which means that 1 with acceptor units is an n-type semiconductor and 2 with donor units is a p-type semiconductor. 13 However, the FET behavior of 1 was not observed in air. The electron mobility and on/off ratio of the film of 1 prepared at 20 °C are 3.4×10^{-3} cm²/V s and 10^{4} , respectively. On the other hand, the hole mobility and on/ off ratio of the film of 2 prepared at 20 °C are 4.5×10^{-3} cm²/V s and 10³, respectively. It should be noted that almost similar mobilities with different polarity were realized by changing the terminal aryl groups. The threshold gate voltages were ca. +75 V for film 1 and ca. -40 V for film 2, suggesting that generation of the charge carrier (electron) in 1 is more difficult. This is related to the high LUMO level of 1.

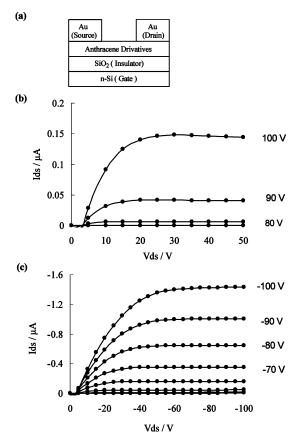


Figure 2. (a) Device structure. Output characteristics of FET devices based on films at the different gate bias: (b) for 1 and (c) for 2.

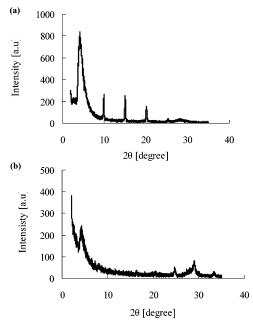


Figure 3. X-ray diffraction of films (50 nm thickness) deposited at room temperature: (a) for $\bf 1$ and (b) for $\bf 2$.

The anthracene films deposited on SiO_2/Si substrates were investigated by X-ray diffraction in reflection mode. Figures 3a and 3b show the thin-film X-ray diffraction (XRD) patterns of **1** and **2** films deposited at 20 °C. In the case of film **1**, the sharp and strong reflections up to the fifth order indicate a high degree of lamellar ordering and crystallinity. The *d*-spacing obtained from the first reflection peak ($2\theta = 4.21$) is 2.09 nm. Since the molecular length of **1** obtained

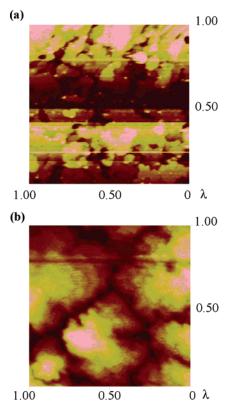


Figure 4. AFM images of films deposited onto Si/SiO_2 : (a) for **1** and (b) for **2**.

from the single-crystal X-ray analysis is 2.02 nm, the molecule of $\bf 1$ is considered to be almost perpendicular on the substrate. This is an ideal molecular arrangement for charge transport. On the other hand, the film $\bf 2$ showed almost no reflection peak, suggesting a disorder orientation on the Si/SiO₂ substrate.

The sublimed films of compounds 1 and 2 are dark blue and shiny. Figure 4 shows noncontact mode atomic-force microscopy (AFM) images of the thin films deposited on

Si/SiO₂. The AFM of **1** film shows a small grain size and rough surface. On the other hand, the AFM of **2** film shows a larger grain size which is estimated to be ca. $0.4-0.6~\mu m$ and each step appears from the surface in the grain. In general, the field-effect mobility for organic semiconductor films depends on the grain size as well as molecular orientation on the substrate. Therefore, the field-effect mobility of **1** film would be improved by making larger crystalline grains on the substrate.

In summary, new anthracene derivatives 1 and 2 were prepared as semiconductors for FETs to prove the effect of terminal groups on charge transport. The n- and p-type activities were achieved by introduction of acceptor or donor units into the anthracene structure. The film of 1 with electron-accepting 4-trifluoromethylphenyl units exhibited good n-type semiconducting behavior. This is the first n-type performance of anthracene derivatives. Since the trifluoromethylphenyl group can be easily introduced by the Suzuki coupling reaction, this group would be used for electron injection in π -conjugated electronic systems. In contrast, the film of 2 with electron-donating thiophene units exhibited p-type semiconducting behavior with the same mobility range observed for the film of 1. This result indicates that the terminal substituents near the gate electrode have a great effect in determining the polarity of FET characteristics.

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Supporting Information Available: Detailed experimental procedures, elemental analyses of **1** and **2**, and X-ray structural information on compound **1** (PDF) and X-ray crystallographic information files (CIF). This material is available free of charge via the Internet at http://pubs.acs.org.

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